



FORM PTO-1449 (modified)  
To: U.S. Department of Commerce  
(PW FORM PAT-1449)  
Patent and Trademark Office

### INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Date: April 27, 2007

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Atty. Dkt. No.	M#	Client Ref.
081468	0305376	P-0362.010-US
Applicant: VAN BILSEN et al.		
Appln. No.: 10/665,404		
Filing Date: September 22, 2003		
Examiner: JOHN R. LEE		Group Art Unit: 2878

#### U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
/JL/	AR 5,721,607 A	02/24/1998	Ota			
BR						
CR						
DR						
ER						
FR						
GR						
HR						
IR						
JR						
KR						

#### FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
					Enclosed	No	Enclose	No
LR								
MR								
NR								
OR								
PR								
QR								
RR								
SR								
TR								
UR								

#### OTHER (Including in this order: Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

VR				
WR				
XR				
YR				
ZR				
AAR				

Examiner /John Lee/ (05/28/2007) Date Considered:

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Atty.  
Dkt. No.

Mr.

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Client Ref.

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## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Date: February 10, 2004

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Applicant: VAN BILSEN et al.

Appln. No.: 10/665,404

Filing Date: September 22, 2003

Examiner: Group Art Unit: 2881

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Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
JL	AR	4,037,969	07/1977	FELDMAN et al.			
	BR	4,236,805	04/1982	FELDMAN et al.			
	CR	4,251,160	02/1981	BOUWHUIS et al.			
	DR	4,355,892	10/1982	MAYER et al.			
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	GR	4,540,277	09/1985	MAYER et al.			
	HR	4,614,432	09/1986	KUNIYOSHI et al.			
	IR	4,690,529	09/1987	SUGIYAMA et al.			
	JR	4,710,026	12/1987	MAGOME et al.			
	KR	4,748,333	05/1988	MIZUTANI et al.			
	LR	4,778,275	10/1988	VAN DEN BRINK et al.			
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	OR	4,857,744	08/1989	KATAOKA et al.			
	PR	4,861,162	08/1989	INA			
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	RR	4,952,970	08/1990	SUZUKI et al.			
	SR	5,100,237	03/1992	WITTEKOEK et al.			
↓	TR	5,114,236	05/1992	MATSUGU et al.			
	UR	5,118,953	06/1992	OTA et al.			

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						Enclosed	No
JL	VR	11-329914	11/1999	Japan	SAKO TAKASHI	X	X
	WR						
	XR						
	YR						

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/JL/	ZR	Markle, D. A., "Submicron 1:1 Optical Lithography", Semi-conductor International, pp. 173-142, May 1986.	X
	AAR		
	BBR		
	CCR		

Examiner /John Lee/ (02/18/2007) Date Considered:

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Examiner's Initials*	Document Number	MM/YYYY	(Family Name of First Inventor)			
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CR	5,160,849	11/1992	OTA et al.			
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MR	5,801,390	09/1998	SHIRAISHI			
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